| L Number | Hits | Search Text | DB | Time stamp |
|--------------|------|---|--------------------|-----------------------|
| _ | 66 | method and (statistical adj outlier\$1) | USPAT; US-PGPUB | 2002/11/01 16:13 |
| _ | 1 | method near2 (statistical adj outlier\$1) | USPAT; | 2002/10/28 |
| | 1 | | US-PGPUB | 20:35 |
|] - | 3247 | ((integrate\$1 or circuit\$1) near2 die) | USPAT; | 2002/10/28 |
| | | and (438/\$.ccls. or 257/\$.ccls. or | US-PGPUB | 21:34 |
| | | 324/\$.ccls.) | | |
| - | 8831 | (semiconductor or (integrate\$1 near | USPAT; | 2002/10/30 |
| | | circuit) or substrate or wafer or die) | US-PGPUB | 23:11 |
| 1 | | and averag\$3 and (absolute adj value\$1) | | |
| - | 42 | (((integrate\$1 or circuit\$1) near2 die) | USPAT; | 2002/10/28 |
| , | | and (438/\$.ccls. or 257/\$.ccls. or | US-PGPUB | 21:31 |
| | 5045 | 324/\$.ccls.)) and (target and average) | Mana. | 2002 (10 (20 |
| - | 3043 | ((semiconductor or (integrate\$1 near circuit) or substrate or wafer or die) | USPAT; US-PGPUB | 2002/10/28 |
| | | and averag\$3 and (absolute adj value\$1)) | US-PGPUB | 21.32 |
| | | and calculat\$3 and difference\$1 | | |
| - | -288 | (-((semiconductor-or -(integrate\$1 near - | USPAT; - | -2002/10/28 |
| | | circuit) or substrate or wafer or die) | US-PGPUB | 21:34 |
| | | and averag\$3 and (absolute adj value\$1)) | | |
| 1 | | and calculat\$3 and difference\$1) and | | |
| | | (438/\$.ccls. or 257/\$.ccls. or | | |
| | | 324/\$.ccls.) | | |
| - | 861 | (438/14).CCLS. | USPAT; | 2002/10/28 |
| | | | US-PGPUB | 21:53 |
| - | 482 | (438/15).CCLS. | USPAT; | 2002/10/28 |
| - | | (420 /17) | US-PGPUB | 21:53 |
| _ | 571 | (438/17).CCLS. | USPAT; | 2002/10/28 |
| _ | 433 | (439/460) CCTS | US-PGPUB | 21:53 |
| - | 433 | (438/460).CCLS. | USPAT; US-PGPUB | 2002/10/28 21:53 |
| _ | 45 | ((438/15).CCLS.) and averag\$3 | USPAT; | 2002/10/28 |
| | | (\150, 15), topic, and averages | US-PGPUB | 21:54 |
| - | 109 | ((438/17).CCLS.) and averag\$3 | USPAT; | 2002/10/28 |
| | | | US-PGPUB | 21:54 |
| - | 40 | ((438/460).CCLS.) and averag\$3 | USPAT; | 2002/10/28 |
| | | | US-PGPUB | 21:54 |
| - | 169 | ((438/14).CCLS.) and averag\$3 | USPAT; | 2002/10/29 |
| | _ | / 00000100F40 41 11 1 | US-PGPUB | 20:29 |
| - | 1 | (US-20020102749-\$).did. | US-PGPUB | 2002/10/28 |
| | 1 | (Mg 30030066860 4) 4:4 | ne perm | 21:56 |
| - | 1 | (US-20020066859-\$).did. | US-PGPUB | 2002/10/28 |
| _ | 1 | (US-6419846-\$).did. | USPAT | 22:01 2002/10/28 |
| | | 100 0310040 Aliana | ODENI | 22:03 |
| - | 1 | (US-6240329-\$).did. | USPAT | 2002/10/28 |
| | | 1, | | 22:10 |
| - | 8202 | (semiconductor or (integrate\$1 near | USPAT; | 2002/10/30 |
| | | circuit) or substrate or wafer or die) | US-PGPUB | 23:12 |
| | | and average and (absolute adj value\$1) | | |
| [- | 1408 | (semiconductor or (integrate\$1 near | USPAT; | 2002/10/30 |
| | , | circuit) or substrate or wafer or die) | US-PGPUB | 23:14 |
| | 2245 | and (average same (absolute adj value\$1)) | 110525 | 2002/17/01 |
| - | 2246 | quiescent adj current | USPAT; | 2002/11/01 |
| _ | 45 | (milescent add gument) and arranged | US-PGPUB USPAT; | 19:01 2002/11/01 |
| - | 45 | <pre>(quiescent adj current) and average\$1 and (absolute adj value\$1)</pre> | USPAT; US-PGPUB | 16:56 |
| _ | 922 | (quiescent adj current) and (wafer or | USPAT; | 2002/11/01 |
| | | substrate or chip or die) | US-PGPUB | 17:07 |
| - | 331 | ((quiescent adj current) and (wafer or | USPAT; | 2002/11/01 |
| | | substrate or chip or die)) and variation | US-PGPUB | 17:09 |
| - | 114 | (quiescent adj current) same variation | USPAT; | 2002/11/01 |
| | | | US-PGPUB | 18:28 |
| - | 0 | iddq and (statistic\$2 near2 outlier\$1) | USPAT; | 2002/11/01 |
| | | | US-PGPUB | 18:29 |
| - | 93 | statistic\$2 near2 outlier\$1 | USPAT; | 2002/11/01 |
| _ | | //mis-a-a-b-add-annuc-t- | US-PGPUB | 18:29 |
| - | 89 | ((quiescent adj current) or iddq) same | USPAT; | 2002/11/01 |
| | | averag\$3 | US-PGPUB | 19:47 |

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| <u>-</u> | 533 | (leakage adj current) same averag\$3 | USPAT; | 2002/11/01 |
|----------|----------|---|----------|------------|
| | | (leanage any callens, bane averages | US-PGPUB | 19:48 |
| _ | 197 | (leakage adj current) same (absolute adj | USPAT; | 2002/11/01 |
| | | value\$1) | US-PGPUB | 19:48 |
| _ | 14 | 1 | USPAT; | 2002/11/01 |
| | | ((leakage adj current) same (absolute adj | US-PGPUB | 19:50 |
| ł | | value\$1)) | | |
| _ | 28785 | calculat\$3 near2 difference\$1 | USPAT; | 2002/11/01 |
| | | | US-PGPUB | 19:51 |
| - | 2866 | calculat\$3 near2 (absolute adj value\$1) | USPAT; | 2002/11/01 |
| | | | US-PGPUB | 19:51 |
| - | 24006 | calculat\$3 near2 averag\$3 | USPAT; | 2002/11/01 |
| 1 | | - | US-PGPUB | 19:51 |
| - | 290 | (calculat\$3 near2 difference\$1) and | USPAT; | 2002/11/01 |
| | | (calculat\$3 near2 (absolute adj value\$1)) | US-PGPUB | 20:03 |
| | | and (calculat\$3 near2 averag\$3) | | |
| - | 194 | ((calculat\$3 near2 difference\$1) and | USPAT; | 2002/11/01 |
|] | | (calculat\$3 near2 (absolute adj value\$1)) | US-PGPUB | 20:08 |
| | | and (calculat\$3 near2 averag\$3)) and | | |
| | | _(device_or wafer or substrate-or— | | |
| | | semiconductor) | | |
| - | 40 | , , | USPAT; | 2002/11/01 |
| | | (calculat\$3 near2 (absolute adj value\$1)) | US-PGPUB | 20:08 |
|] | | and (calculat\$3 near2 averag\$3)) and | | |
| L | <u>L</u> | (wafer or substrate or semiconductor) | | 1 |